Search Notes

Applicant(s)/Patent under Reexamination

FURUHASHI ET AL.

10/696,775

Examiner

Art Unit

Stephen W. Smoot

2813

SEARCHED				
Class	Subclass	Date	Examiner	
438	301	5/11/2005	sws	
438	303	5/11/2005	sws	
438	675	5/11/2005	sws	
438	786	5/11/2005	sws	
438	791	5/11/2005	sws	
427	249.15	5/11/2005	sws	
427	255.27	5/11/2005	sws	
427	255.28	5/11/2005	sws	
427	255.393	5/11/2005	sws	
427	255.394	5/11/2005	sws .	

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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	SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
		DATE	EXMR			
	Key Words: BTBAS - Bis Tertiary Butyl Amino Silane; Hydrazine, Azido; SiN - Nitride, SiCN - Carbonitride, SiOCN;	5/11/2005	I.U.J.			
	Pocket Implants; Damascene Structure - Etch Stop Layer; Sacrificial Spacer.	5/12/2005	J.W.S. sws			
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	Search Tools - EAST (attached): USPAT; US PG PUBS; Derwent; EPO; JPO; IBM TDB	5/11/2005	LW.L. sws			